

## LM2722 High Speed Synchronous/Asynchronous MOSFET Driver

Check for Samples: [LM2722](#)

### FEATURES

- Synchronous or Asynchronous Operation
- Adaptive Shoot-Through Protection
- Input Under-Voltage-Lock-Out
- Typical 20ns Internal Delay
- Plastic 8-pin SOIC package

### APPLICATIONS

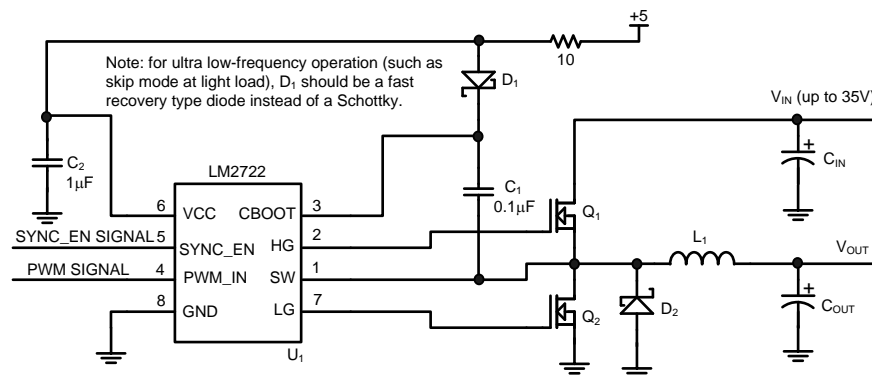
- Driver for LM2723 Intel Mobile Northwood CPU Core Power Supply.
- High Current DC/DC Power Supplies
- High Input Voltage Switching Regulators
- Fast Transient Microprocessors

### DESCRIPTION

The LM2722, part of the LM2726 family, is designed to be used with multi-phase controllers. This part differs from the LM2726 by changing the functionality of the SYNC\_EN pin from a whole chip enable to a low side MOSFET enable. As a result, the SYNC\_EN pin now provides control between Synchronous and Asynchronous operations. Having this control can be advantageous in portable systems since Asynchronous operations can be more efficient at very light loads.

The LM2722 drives both top and bottom MOSFETs in a push-pull structure simultaneously. It takes a logic level PWM input and splits it into two complimentary signals with a typical 20ns dead time in between. The built-in cross-conduction protection circuitry prevents the top and bottom FETs from turning on simultaneously. The cross-conduction protection circuitry detects both the driver outputs and will not turn on a driver until the other driver output is low. With a bias voltage of 5V, the peak sourcing and sinking current for each driver of the LM2722 is typically 3A. In an SOIC-8 package, each driver is able to handle 50mA average current. Input UVLO (Under-Voltage-Lock-Out) forces both driver outputs low to ensure proper power-up and power-down operation. The gate drive bias voltage needed by the high side MOSFET is obtained through an external bootstrap. Minimum pulse width is as low as 55ns.

### Typical Application



### NOTE

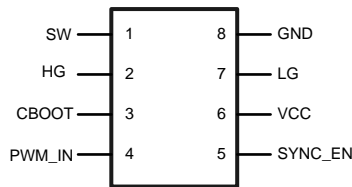
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## Connection Diagram



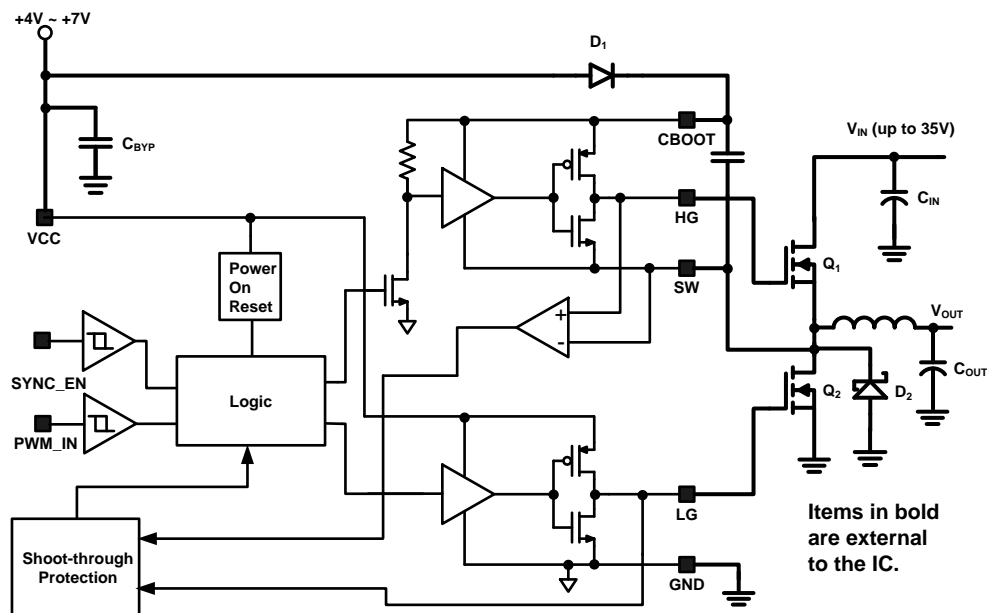
**Figure 1. SOIC (D)  
(Top View)**

## Pin Functions

### Pin Descriptions

Pin	Name	Function
1	SW	Top driver return. Should be connected to the common node of top and bottom FETs
2	HG	Top gate drive output
3	CBOOT	Bootstrap. Accepts a bootstrap voltage for powering the high-side driver
4	PWM_IN	Accepts a 5V-logic control signal
5	SYNC_EN	Low gate Enable
6	VCC	Connect to +5V supply
7	LG	Bottom gate drive output
8	GND	Ground

## Block Diagram



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

### Absolute Maximum Ratings <sup>(1)</sup>

VCC	7.5V
CBOOT	42V
CBOOT to SW	8V
SW to PGND	36V
Junction Temperature	+150°C
Power Dissipation (2)	720mW
Storage Temperature	-65° to 150°C
ESD Susceptibility Human Body Model <sup>(3)</sup>	1kV
Soldering Time, Temperature	10sec., 300°C

- (1) **Absolute Maximum Ratings** are limits beyond which damage to the device may occur. **Operating ratings** are conditions under which the device operates correctly. Operating Ratings do not imply ensured performance limits.
- (2) Maximum allowable power dissipation is a function of the maximum junction temperature,  $T_{JMAX}$ , the junction-to-ambient thermal resistance,  $\theta_{JA}$ , and the ambient temperature,  $T_A$ . The maximum allowable power dissipation at any ambient temperature is calculated using:  $P_{MAX} = (T_{JMAX} - T_A) / \theta_{JA}$ . The junction-to-ambient thermal resistance,  $\theta_{JA}$ , for the LM2722, it is 172°C/W. For a  $T_{JMAX}$  of 150°C and  $T_A$  of 25°C, the maximum allowable power dissipation is 0.7W.
- (3) ESD machine model susceptibility is 100V.

### Operating Ratings <sup>(1)</sup>

VCC	4V to 7V
Junction Temperature Range	-40° to 125°C

- (1) **Absolute Maximum Ratings** are limits beyond which damage to the device may occur. **Operating ratings** are conditions under which the device operates correctly. Operating Ratings do not imply ensured performance limits.

## Electrical Characteristics

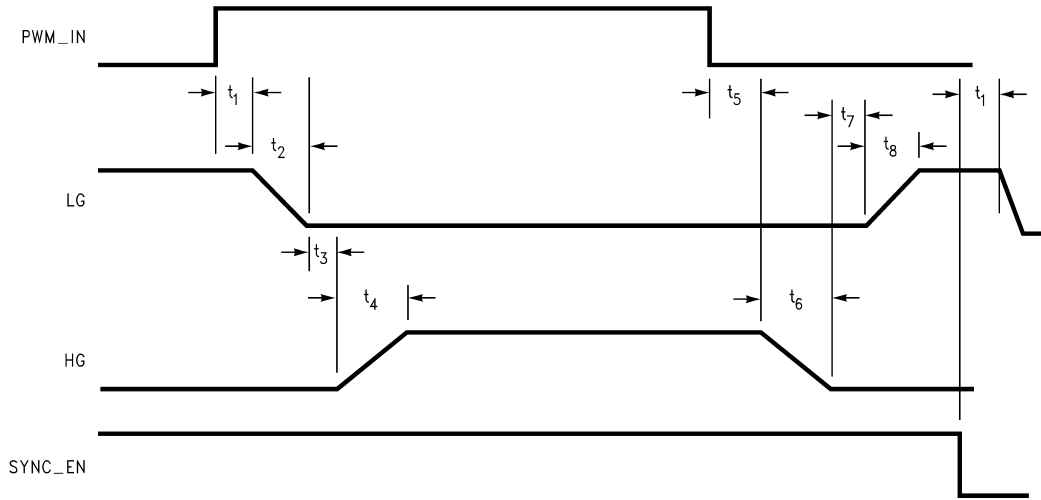
VCC = CBOOT = 5V, SW = GND = 0V, unless otherwise specified. Typical and limits appearing in plain type apply for  $T_A = T_J = +25^\circ\text{C}$ . Limits appearing in **boldface** type apply over the entire operating temperature range.

Symbol	Parameter	Condition	Min	Typ	Max	Units
<b>POWER SUPPLY</b>						
$I_{q\_op}$	Operating Quiescent Current	PWM_IN = 0V		190	<b>300</b>	$\mu\text{A}$
<b>TOP DRIVER</b>						
	Peak Pull-Up Current	Test Circuit 1, $V_{bias} = 5\text{V}$ , $R = 0.1\Omega$		3.0		A
	Pull-Up Rds_on	$I_{CBOOT} = I_{HG} = 0.7\text{A}$		1.0		$\Omega$
	Peak Pull-down Current	Test Circuit 2, $V_{bias} = 5\text{V}$ , $R = 0.1\Omega$		-3.2		A
	Pull-down Rds_on	$I_{SW} = I_{HG} = 0.7\text{A}$		0.5		$\Omega$
$t_4$	Rise Time	Timing Diagram, $C_{LOAD} = 3.3\text{nF}$		17		ns
$t_6$	Fall Time			12		ns
$t_3$	Pull-Up Dead Time	Timing Diagram		23		ns
$t_5$	Pull-Down Delay	Timing Diagram, from PWM_IN Falling Edge		27		ns
<b>BOTTOM DRIVER</b>						
	Peak Pull-Up Current	Test Circuit 3, $V_{bias} = 5\text{V}$ , $R = 0.1\Omega$		3.2		A
	Pull-up Rds_on	$I_{VCC} = I_{LG} = 0.7\text{A}$		1.0		$\Omega$
	Peak Pull-down Current	Test Circuit 4, $V_{bias} = 5\text{V}$ , $R = 0.1\Omega$		3.2		A
	Pull-down Rds_on	$I_{GND} = I_{LG} = 0.7\text{A}$		0.5		$\Omega$
$t_8$	Rise Time	Timing Diagram, $C_{LOAD} = 3.3\text{nF}$		17		ns
$t_2$	Fall Time			14		ns
$t_7$	Pull-up Dead Time	Timing Diagram		28		ns
$t_1$	Pull-down Delay	Timing Diagram, from PWM_IN Rising Edge		13		ns
<b>LOGIC</b>						
$V_{uvlo\_up}$	Power On Threshold	VCC rises from 0V toward 5V	<b>4</b>	3.7		V
$V_{uvlo\_dn}$	Under-Voltage-Lock-Out Threshold			3.0	<b>2.5</b>	V
$V_{uvlo\_hys}$	Under-Voltage-Lock-Out Hysteresis			0.7		V
$V_{IH\_EN}$	SYNC_EN Pin High Input		<b>2.4</b>			V
$V_{IL\_EN}$	SYNC_EN Pin Low Input				<b>0.8</b>	V
$I_{leak\_EN}$	SYNC_EN Pin Leakage Current	EN = 5V	<b>-2</b>		<b>2</b>	$\mu\text{A}$
		EN = 0V	<b>-2</b>		<b>2</b>	
$t_{on\_min}$	Minimum Positive Input Pulse Width (1)			55		ns
$t_{off\_min}$	Minimum Negative Input Pulse Width (2)			55		
$V_{IH\_PWM}$	PWM_IN High Level Input Voltage	When PWM_IN pin goes high from 0V	<b>2.4</b>			V
$V_{IL\_PWM}$	PWM_IN Low Level Input Voltage	When PWM_IN pin goes low from 5V			<b>0.8</b>	

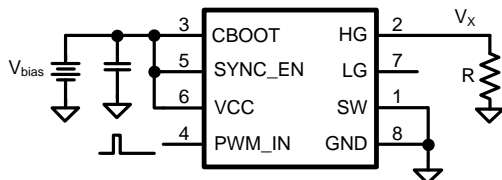
- (1) If after a rising edge, a falling edge occurs sooner than the specified value, the IC may intermittently fail to turn on the bottom gate when the top gate is off. As the falling edge occurs sooner and sooner, the driver may start to ignore the pulse and produce no output.
- (2) If after a falling edge, a rising edge occurs sooner than the specified value, the IC may intermittently fail to turn on the top gate when the bottom gate is off. As the rising edge occurs sooner and sooner, the driver may start to ignore the pulse and produce no output.

TEST CIRCUIT DIAGRAMS

Timing Diagram

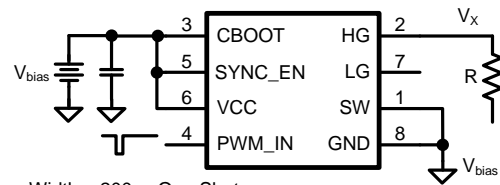


Test Circuits



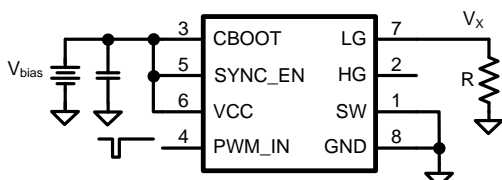
Width = 200ns, One Shot.

Figure 2. Test Circuit 1



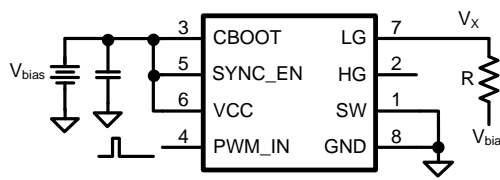
Width = 200ns, One Shot

Figure 3. Test Circuit 2



Width = 200ns, One Shot

Figure 4. Test Circuit 3



Width = 200ns, One Shot

Figure 5. Test Circuit 4

$$I_{\text{pull\_up}} = \frac{V_x}{R} \tag{1}$$

$$I_{\text{pull\_down}} = \frac{V_{\text{bias}} - V_x}{R} \tag{2}$$

$$R_{\text{ds\_pull\_up}} = \frac{V_{\text{bias}} - V_x}{V_x} \cdot R \tag{3}$$

$$R_{\text{ds\_pull\_down}} = \frac{V_x}{V_{\text{bias}} - V_x} \cdot R \tag{4}$$

## Typical Waveforms

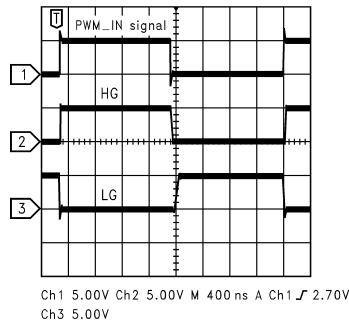


Figure 6. Switching Waveforms of Test Circuit

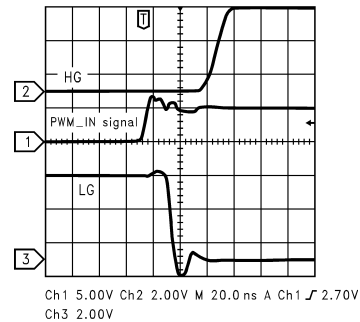


Figure 7. When Input Goes High

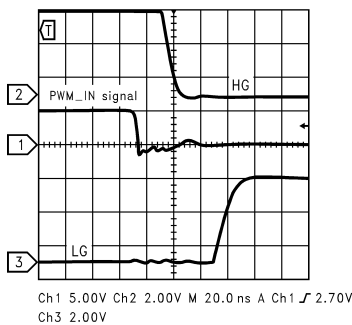


Figure 8. When Input Goes Low

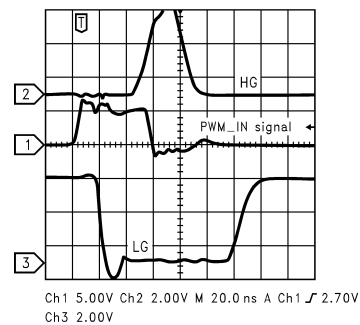


Figure 9. Minimum Positive Pulse

## Application Information

### MINIMUM PULSE WIDTH

In order for the shoot-through prevention circuitry in the LM2722 to work properly, the pulses into the PWM\_IN pin must be longer than 55ns. The internal logic waits until the first FET is off plus 20ns before turning on the opposite FET. If, after a falling edge, a rising edge occurs sooner than the specified time,  $t_{off\_min}$ , the IC may intermittently fail to turn on the top gate when the bottom gate is off. As the rising edge occurs sooner and sooner, the driver may start to ignore the pulse and produce no output. This condition results in the PWM\_IN pin in a high state and neither FET turned on. To get out of this state, the PWM\_IN pin must see a low signal for greater than 55ns, before the rising edge.

This will also assure that the gate drive bias voltage has been restored by forcing the top FET source and  $C_{boot}$  to ground first. Then the internal circuitry is reset and normal operation will resume.

Conversely, if, after a rising edge, a falling edge occurs sooner than the specified minimum pulse width,  $t_{on\_min}$ , the IC may intermittently fail to turn on the bottom FET. As the falling edge occurs sooner and sooner, the driver will start to ignore the pulse and produce no output. This will result in the  $t_{off}$  inductor current taking a path through a diode provided for non-synchronous operation. The circuit will resume synchronous operation when the rising PWM pulses exceed 55ns in duration.

### HIGH INPUT VOLTAGES OR HIGH OUTPUT CURRENTS

At input voltages above twice the output voltage and at higher power levels, the designer may find snubber networks and gate drive limiting useful in reducing EMI and preventing injurious transients. A small resistor, 1 $\Omega$  to 5 $\Omega$ , between the driver outputs and the MOSFET gates will slightly increase the rise time and fall time of the output stage and reduce switching noise. The trade-off is 1% to 2% in efficiency.

A series R-C snubber across in parallel with the bottom FET can also be used to reduce ringing. Values of 10nF and 10 $\Omega$  to 100 $\Omega$  are a good starting point.

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**REVISION HISTORY**

<b>Changes from Revision C (March 2013) to Revision D</b>	<b>Page</b>
<hr/> <ul style="list-style-type: none"><li>• Changed layout of National Data Sheet to TI format .....</li></ul>	<hr/> <b>6</b>

**PACKAGING INFORMATION**

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
LM2722MX/NOPB	LIFEBUY	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU SN	Level-1-260C-UNLIM		2722 M	

(1) The marketing status values are defined as follows:

**ACTIVE:** Product device recommended for new designs.

**LIFEBUY:** TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

**NRND:** Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSELETE:** TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

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**Green:** TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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